This listing of claims will replace all prior versions and listings of claims in the

application:

LISTING OF CLAIMS:

1. (original): A gallium nitride compound semiconductor light-emitting device comprising:

a crystalline substrate (10);

a light-emitting layer (15) of a quantum well structure which is formed of a gallium

nitride compound semiconductor barrier layer and a gallium nitride compound semiconductor

well layer, which light-emitting layer is provided on a second side of the crystalline substrate;

a contact layer (17) formed of a Group III-V compound semiconductor for providing an

Ohmic electrode for supplying device operation current to the light-emitting layer; and

an Ohmic electrode (18) which is provided on the contact layer and has an aperture

through which a portion of the contact layer is exposed,

wherein the Ohmic electrode exhibits light permeability with respect to light emitted

from the light-emitting layer, and the well layer contains a thick portion having a large thickness

and a thin portion having a small thickness.

2. (original): A gallium nitride compound semiconductor light-emitting device according to

claim 1, wherein the well layer contains a portion having a thickness of 1.5 nm to 0 nm.

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3. (currently amended): A gallium nitride compound semiconductor light-emitting device according to claim 1-or claim 2, wherein either the barrier layer or the well layer is doped with an impurity element.

4. (original): A gallium nitride compound semiconductor light-emitting device according to claim 3, wherein only the barrier layer is doped with an impurity element.

5. (original): A gallium nitride compound semiconductor light-emitting device according to claim 4, wherein the predetermined impurity element added only to the barrier layer is silicon.

6. (currently amended): A gallium nitride compound semiconductor light-emitting device according to claim 1 any one of claims 1 to 5, wherein the contact layer (17) is doped with an n-type impurity element and has a carrier concentration of 5×10^{18} cm⁻³ to 2×10^{19} cm⁻³.

7. (currently amended): A gallium nitride compound semiconductor light-emitting device according to claim 1 any one-of claims 1 to 6, wherein the contact layer (17) is doped with a ptype impurity element and has a carrier concentration of 1×10^{17} cm⁻³ to 1×10^{19} cm⁻³.

8. (original): A gallium nitride compound semiconductor light-emitting device according to claim 7, wherein the contact layer (17) is doped with a p-type impurity element and has a carrier concentration of 1×10^{17} cm⁻³ to 5×10^{18} cm⁻³.

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9. (currently amended): A gallium nitride compound semiconductor light-emitting device

according to claim 1 any one of claims 1 to 8, wherein the contact layer (17) has a thickness of 1

 μm to 3 μm .

10. (currently amended): A gallium nitride compound semiconductor light-emitting device

according to claim 1 any one of claims 1 to 9, wherein the Ohmic electrode (18) exhibits a

transmittance at the wavelength of emitted light of 30% or higher.

11. (currently amended): A gallium nitride compound semiconductor light-emitting device

according to claim 1 any one of claims 1 to 10, wherein the Ohmic electrode (18) has a thickness

of 1 nm to 100 nm.

12. (currently amended): A gallium nitride compound semiconductor light-emitting device

according to claim 1 any one of claims 1 to 11, further comprising a metallic reflecting mirror

(21) for reflecting light emitted from the light-emitting layer (15) to the outside, which mirror is

provided on a first side of the crystalline substrate (10), wherein the metallic reflecting mirror

(21) contains a metallic material identical to that contained in the Ohmic electrode (18).

13. (original): A gallium nitride compound semiconductor light-emitting device according to

claim 12, wherein the metallic reflecting mirror (18) has a multilayer structure including a

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metallic film which contains a metallic material identical to that contained in the Ohmic

electrode (18).

14. (currently amended): A gallium nitride compound semiconductor light-emitting device

according to claim lany one of claims 1 to 13, wherein the metallic reflecting mirror (21)

contains a single-metal film or an alloy film formed from at least one member selected from the

group consisting of silver, platinum, rhodium and aluminum.

15. (currently amended): A gallium nitride compound semiconductor light-emitting device

according to claim 1 any one of claims 1 to 14, wherein the metallic reflecting mirror (21) is in

the form of multilayer film.

16. (currently amended): A light-emitting diode employing the gallium nitride compound

semiconductor light-emitting device according to claim 1.any one of claims 1 to 15.

17. (currently amended): A lamp employing the gallium nitride compound semiconductor light-

emitting device according to claim 1.any one of claims 1 to 15 or the light emitting diode

according to claim 16.

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